

Vapochromism associated with the changes in the molecular arrangement of organic crystals

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1. General experimental procedures

X-Ray measurements at 298K and 123 K were made on a Rigaku RAXIS RAPID II imaging plate area detector with graphite monochromated Cu-K α radiation. All calculations were performed using the CrystalStructure crystallographic software package except for refinement, which was performed using SHELXL-97. All structures were solved by a combination of direct methods and difference Fourier syntheses, and refined by full-matrix leastsquares on F₂, by using the SHELXTL software package. Powder X-ray diffraction profiles were recorded using a Regaku Ultima IV with monochromated Cu-K α radiation ($\lambda = 1.54184$ Å, 50 kV, 40 mA, scan speed 2.0°/min, scan range 4 - 60°) equipped with a cross-beam optics system consisting of a PSA100U parallel slip analyzer. Thermogravimetric analyses were carried out using a TG-DTA2000SA instrument manufactured by Bruker. Three to five milligrams of the crystal samples were heated from 25°C to 150°C in aluminum pans with 5 mm in diameter. A ramping rate of 5 °C/min was used with a nitrogen purge rate of 150 mL/min. DSC measurements were carried out using a Burker DSC3100SA. In all the experiments the samples were examined in a sealed pan under nitrogen atmosphere. UV-vis reflection spectra were measured using a JASCO V-650.

2. General procedure for X-ray structural analyses

Data Collection for 1b·HCl

A yellow prism crystal of $C_{16}H_{16}ClNO_2$ having approximate dimensions of 0.300 x 0.200 x 0.200 mm was mounted on a CryoLoop. All measurements were made on a Rigaku R-Axis RAPID diffractometer using graphite monochromated Cu-K α radiation.

The data were collected at a temperature of $-150 \pm 1^\circ\text{C}$ to a maximum 2θ value of 136.5° . A total of 60 oscillation images were collected. A sweep of data was done using ω scans from 80.0 to 260.0° in 15.0° step, at $\chi=54.0^\circ$ and $\phi = 0.0^\circ$. The exposure rate was 20.0 [sec./ $^\circ$]. A second sweep was performed using ω scans from 80.0 to 260.0° in 15.0° step, at $\chi=54.0^\circ$ and $\phi = 90.0^\circ$. The exposure rate was 20.0 [sec./ $^\circ$]. Another sweep was performed using ω scans from 80.0 to 260.0° in 15.0° step, at $\chi = 54.0^\circ$ and $\phi = 180.0^\circ$. The exposure rate was 20.0 [sec./ $^\circ$]. Another sweep was performed using ω scans from 80.0 to 260.0° in 15.0° step, at $\chi = 54.0^\circ$ and $\phi = 270.0^\circ$. The exposure rate was 20.0 [sec./ $^\circ$]. Another sweep was performed using ω scans from 80.0 to 260.0° in 15.0° step, at $\chi = 0.0^\circ$ and $\phi = 0.0^\circ$. The exposure rate was 20.0 [sec./ $^\circ$]. The crystal-to-detector distance was 127.40 mm. Readout was performed in the 0.100 mm pixel mode.

Data Reduction

Of the 15692 reflections that were collected, 2621 were unique ($R_{\text{int}} = 0.0445$).

The linear absorption coefficient, μ , for Cu-K α radiation is 23.786 cm^{-1} . The data were corrected for Lorentz and polarization effects.

Structure Solution and Refinement

The structure was solved by direct methods¹ and expanded using Fourier techniques. The non-hydrogen atoms were refined anisotropically. Hydrogen atoms were refined using the riding model. The final cycle of full-matrix least-squares refinement² on F^2 was based on 2621 observed reflections and 182 variable parameters and converged (largest parameter shift was 0.00 times its esd) with unweighted and weighted agreement factors of:

$$R1 = \sum ||F_o| - |F_c|| / \sum |F_o| = 0.0370$$

$$wR2 = [\sum (\omega (F_o^2 - F_c^2)^2) / \sum \omega(F_o^2)^2]^{1/2} = 0.1004$$

The standard deviation of an observation of unit weight³ was 1.07. Unit weights were

used. The maximum and minimum peaks on the final difference Fourier map corresponded to 0.29 and -0.19 e⁻/Å³, respectively.

Neutral atom scattering factors were taken from Cromer and Waber⁵. Anomalous dispersion effects were included in F_{calc}⁶; the values for Δf' and Δf'' were those of Creagh and McAuley.⁷ The values for the mass attenuation coefficients are those of Creagh and Hubbell.⁸ All calculations were performed using the CrystalStructure⁹ crystallographic software package except for refinement, which was performed using SHELXL-97.¹⁰ Crystal data, data collection parameters, and results of the analyses are listed in Tables S1-S3.

References

(1) SIR92: Altomare, A., Cascarano, G., Giacovazzo, C., Guagliardi, A., Burla, M., Polidori, G., and Camalli, M. (1994) *J. Appl. Cryst.*, 27, 435.

(2) Least Squares function minimized: (SHELXL97)

$$\sum w(F_o^2 - F_c^2)^2 \quad \text{where } w = \text{Least Squares weights.}$$

(3) Standard deviation of an observation of unit weight:

$$[\sum w(F_o^2 - F_c^2)^2 / (N_o - N_v)]^{1/2}$$

where: N_o = number of observations

N_v = number of variables

(4) Flack, H. D. (1983), *Acta Cryst.* A39, 876-881.

(5) Cromer, D. T. & Waber, J. T.; "International Tables for X-ray Crystallography", Vol. IV, The Kynoch Press, Birmingham, England, Table 2.2 A (1974).

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(9) CrystalStructure 4.0: Crystal Structure Analysis Package, Rigaku Corporation (2000-2010). Tokyo 196-8666, Japan.

(10) SHELX97: Sheldrick, G.M. (2008). *Acta Cryst.* A64, 112-122.

2-1. X-ray structural analysis of **1a**·HCl·H₂O

A. Crystal Data

Empirical Formula	C ₁₅ H ₁₆ O ₃ NCl
Formula Weight	293.75
Crystal Color, Habit	red, block
Crystal Dimensions	0.80 X 0.20 X 0.15 mm
Crystal System	monoclinic
Lattice Type	Primitive
Indexing Images	3 oscillations @ 180.0 seconds
Detector Position	127.40 mm
Pixel Size	0.100 mm
Lattice Parameters	a = 5.19126(15) Å b = 33.4280(10) Å c = 9.2170(3) Å β = 112.0213(14) ° V = 1482.77(8) Å ³
Space Group	P2 ₁ /n (#14)
Z value	4
D _{calc}	1.316 g/cm ³
F ₀₀₀	616.00
m(CuKα)	23.440 cm ⁻¹
Diffractometer	Rigaku RAXIS-RAPID
Radiation	CuKα (λ = 1.54187 Å) graphite monochromated
2θ _{max}	136.5°
No. of Reflections Measured	Total: 23293 Unique: 2669 (R _{int} = 0.074)
Corrections	Lorentz-polarization Secondary Extinction (coefficient: 3.55000e-003)

B. Structure Solution and Refinement

Structure Solution	Direct Methods (SIR92)
Refinement	Full-matrix least-squares on F^2
Function Minimized	$\sum w (F_o^2 - F_c^2)^2$
Least Squares Weights	$w = 1 / [\sigma^2(F_o^2) + (0.0775 \cdot P)^2 + 0.2230 \cdot P]$ where $P = (\text{Max}(F_o^2, 0) + 2F_c^2)/3$
$2\theta_{\text{max}}$ cutoff	136.5 $^\circ$
Anomalous Dispersion	All non-hydrogen atoms
No. Observations (All reflections)	2669
No. Variables	191
Reflection/Parameter Ratio	13.97
Residuals: R1 ($I > 2.00\sigma(I)$)	0.0500
Residuals: R (All reflections)	0.0600
Residuals: wR2 (All reflections)	0.1510
Goodness of Fit Indicator	1.113
Max Shift/Error in Final Cycle	0.000
Maximum peak in Final Diff. Map	0.32 e $^-/\text{\AA}^3$
Minimum peak in Final Diff. Map	-0.25 e $^-/\text{\AA}^3$

2-2. X-ray structural analysis of **1b**·HCl

A. Crystal Data

Empirical Formula	C ₁₆ H ₁₆ ClNO ₂
Formula Weight	289.76
Crystal Color, Habit	yellow, prism
Crystal Dimensions	0.300 X 0.200 X 0.200 mm
Crystal System	monoclinic
Lattice Type	Primitive
Lattice Parameters	a = 7.1274(2) Å b = 12.8781(3) Å c = 15.9623(5) Å β = 103.450(2) ° V = 1424.95(6) Å ³
Space Group	P2 ₁ /c (#14)
Z value	4
D _{calc}	1.351 g/cm ³
F ₀₀₀	608.00
m(CuKα)	23.786 cm ⁻¹
Diffractometer	R-AXIS RAPID
Radiation	CuKα (λ = 1.54187 Å) graphite monochromated
Voltage, Current	50kV, 100mA
Temperature	-150.0°C
2θ _{max}	136.4°
No. of Reflections Measured	Total: 15692 Unique: 2621 (R _{int} = 0.0445)
Corrections	Lorentz-polarization

B. Structure Solution and Refinement

Structure Solution	Direct Methods (SHELX97)
Refinement	Full-matrix least-squares on F^2
Function Minimized	$\sum w (F_o^2 - F_c^2)^2$
Least Squares Weights	$w = 1 / [\sigma^2(F_o^2) + (0.0495 \cdot P)^2 + 0.5911 \cdot P]$ where $P = (\text{Max}(F_o^2, 0) + 2F_c^2)/3$
$2\theta_{\text{max}}$ cutoff	136.4 $^\circ$
Anomalous Dispersion	All non-hydrogen atoms
No. Observations (All reflections)	2621
No. Variables	182
Reflection/Parameter Ratio	14.40
Residuals: R1 ($I > 2.00\sigma(I)$)	0.0370
Residuals: R (All reflections)	0.0432
Residuals: wR2 (All reflections)	0.1004
Goodness of Fit Indicator	1.073
Max Shift/Error in Final Cycle	0.001
Maximum peak in Final Diff. Map	0.29 e $^-/\text{\AA}^3$
Minimum peak in Final Diff. Map	-0.19 e $^-/\text{\AA}^3$

2-3. X-ray structural analysis of **1b**·HCl·H₂O

A. Crystal Data

Empirical Formula	C ₁₆ H ₁₈ ClNO ₃
Formula Weight	307.78
Crystal Color, Habit	unknown, platelet
Crystal Dimensions	0.500 X 0.200 X 0.050 mm
Crystal System	triclinic
Lattice Type	Primitive
Lattice Parameters	a = 4.88516(18) Å b = 8.6653(3) Å c = 18.6176(7) Å α = 86.980(3) ° β = 85.549(3) ° γ = 80.147(2) ° V = 773.52(5) Å ³
Space Group	P-1 (#2)
Z value	2
D _{calc}	1.321 g/cm ³
F ₀₀₀	324.00
m(CuKα)	22.702 cm ⁻¹
Diffractometer	R-AXIS RAPID
Radiation	CuKα (λ = 1.54187 Å) graphite monochromated
Voltage, Current	50kV, 100mA
Temperature	-150.0°C
2θ _{max}	136.4°
No. of Reflections Measured	Total: 8223 Unique: 2764 (R _{int} = 0.0865)
Corrections	Lorentz-polarization

B. Structure Solution and Refinement

Structure Solution	Direct Methods (SHELX97)
Refinement	Full-matrix least-squares on F^2
Function Minimized	$\sum w (F_o^2 - F_c^2)^2$
Least Squares Weights	$w = 1 / [\sigma^2(F_o^2) + (0.0514 \cdot P)^2 + 0.0000 \cdot P]$ where $P = (\text{Max}(F_o^2, 0) + 2F_c^2)/3$
$2\theta_{\text{max}}$ cutoff	136.4 $^\circ$
Anomalous Dispersion	All non-hydrogen atoms
No. Observations (All reflections)	2764
No. Variables	198
Reflection/Parameter Ratio	13.96
Residuals: R1 ($I > 2.00\sigma(I)$)	0.0549
Residuals: R (All reflections)	0.0777
Residuals: wR2 (All reflections)	0.1249
Goodness of Fit Indicator	0.923
Max Shift/Error in Final Cycle	0.000
Maximum peak in Final Diff. Map	0.43 e $^-/\text{\AA}^3$
Minimum peak in Final Diff. Map	-0.29 e $^-/\text{\AA}^3$

3. TG-DTA measurements of $1a \cdot HCl$ after exposure to H_2O vapor

TG-DTA measurements of compound $1a \cdot HCl$ after exposure to water vapor were carried out in the temperature interval $25^\circ C - 150^\circ C$ at a heating rate of $5^\circ C/min$. After exposure for 7 days, a peak at $85^\circ C$ was observed with a 2.67 wt% loss, which is corresponding to a loss of 0.5 water molecule. After exposure for 10 days, a peak at $85^\circ C$ was observed with a 5.40 wt% loss, which is corresponding to a loss of 1.0 water molecule.

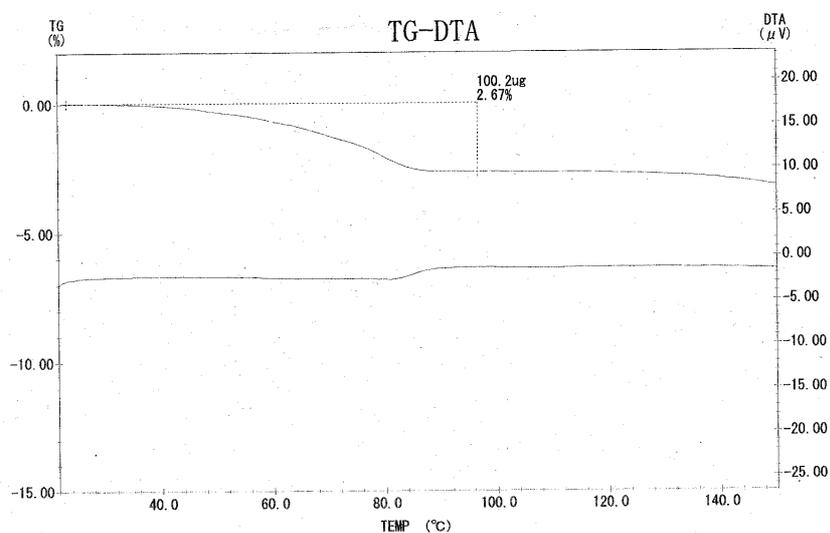


Figure S1. TG-DTA data for $1a \cdot HCl$ after exposure to water vapor for 7 days.

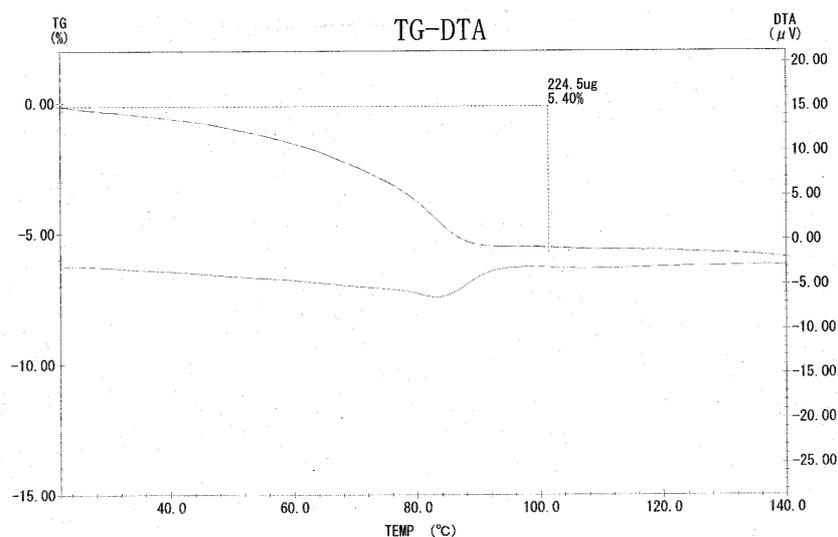


Figure S2. TG-DTA data for $1a \cdot HCl$ after exposure to water vapor for 10 days.

4. PXRD patterns of $1b \cdot HCl \cdot H_2O$ after heating and $1b \cdot HCl$ after exposure to H_2O vapor

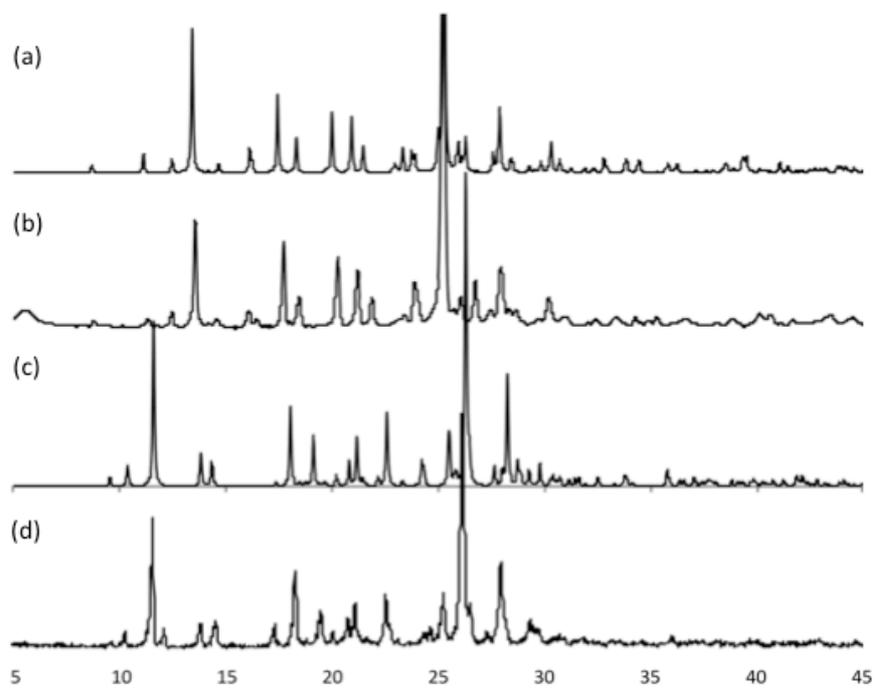


Figure S3. Simulated PXRD patterns for (a) $1b \cdot HCl$ and (c) $1b \cdot HCl \cdot H_2O$, and PXRD patterns for (b) $1b \cdot HCl \cdot H_2O$ after heating at 80°C for 5h, and the dehydrate $1b \cdot HCl$ after exposure to H_2O vapor for (d) 2 days.